

TOSHIBA Field Effect Transistor Silicon P Channel MOS Type

SSM6P09FU

High Speed Switching Applications

- Small package
- Low Drain-Source ON resistance.
 - : $R_{on} = 2.7 \Omega$ (max) (@ $V_{GS} = -10 V$)
 - : $R_{on} = 4.2 \Omega$ (max) (@ $V_{GS} = -4 V$)

Absolute Maximum Ratings ($T_a = 25^\circ C$) (Q1, Q2 Common)

Characteristics	Symbol	Rating	Unit
Drain-Source voltage	V_{DS}	-30	V
Gate-Source voltage	V_{GSS}	± 20	V
Drain current	DC	I_D	-200
	Pulse	I_{DP}	-800
Drain power dissipation ($T_a = 25^\circ C$)	P_D (Note 1)	300	mW
Channel temperature	T_{ch}	150	$^\circ C$
Storage temperature range	T_{stg}	-55~150	$^\circ C$

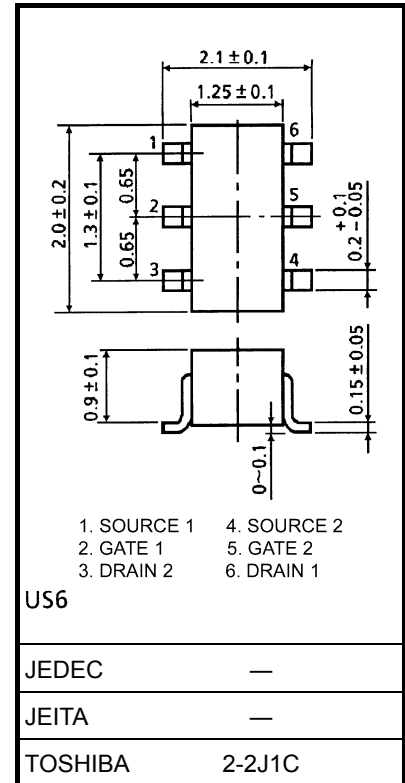
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Total rating, mounted on FR4 board
(25.4 mm × 25.4 mm × 1.6 t, Cu Pad: 0.32 mm² × 6) Figure 1.

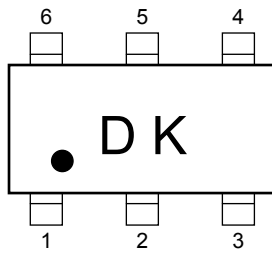
Handling Precaution

When handling individual devices (which are not yet mounting on a circuit board), be sure that the environment is protected against electrostatic electricity. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

Unit: mm



Marking



Equivalent Circuit (top view)

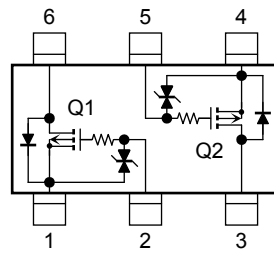
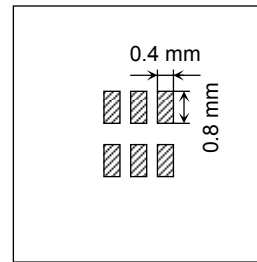


Figure 1: 25.4 mm × 25.4 mm × 1.6 t, Cu Pad: 0.32 mm² × 6



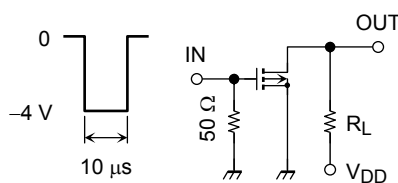
Electrical Characteristics (Ta = 25°C) (Q1, Q2 common)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current	I_{GSS}	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0$	—	—	± 1	μA
Drain-Source breakdown voltage	$V_{(BR)DSS}$	$I_D = -1 \text{ mA}, V_{GS} = 0$	-30	—	—	V
Drain cut-off current	I_{DSS}	$V_{DS} = -30 \text{ V}, V_{GS} = 0$	—	—	-1	μA
Gate threshold voltage	V_{th}	$V_{DS} = -5 \text{ V}, I_D = -0.1 \text{ mA}$	-1.1	—	-1.8	V
Forward transfer admittance	$ Y_{fs} $	$V_{DS} = -5 \text{ V}, I_D = -100 \text{ mA}$ (Note2)	115	—	—	mS
Drain-Source ON resistance	$R_{DS(ON)}$	$I_D = -100 \text{ mA}, V_{GS} = -10 \text{ V}$ (Note2)	—	2.1	2.7	Ω
		$I_D = -100 \text{ mA}, V_{GS} = -4 \text{ V}$ (Note2)	—	3.3	4.2	
		$I_D = -100 \text{ mA}, V_{GS} = -3.3 \text{ V}$ (Note2)	—	4.0	6.0	
Input capacitance	C_{iss}	$V_{DS} = -5 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	—	22	—	pF
Reverse transfer capacitance	C_{rss}	$V_{DS} = -5 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	—	5	—	pF
Output capacitance	C_{oss}	$V_{DS} = -5 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	—	14	—	pF
Switching time	Turn-on time	t_{on}	—	85	—	ns
	Turn-off time	t_{off}				

Note2: Pulse test

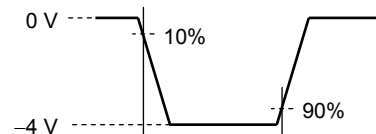
Switching Time Test Circuit (Q1, Q2 Common)

(a) Test circuit

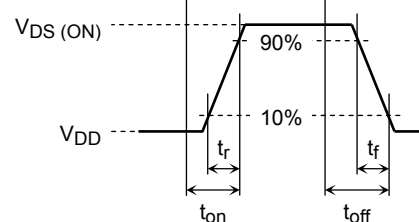


$V_{DD} = -5 \text{ V}$
 Duty $\leq 1\%$
 V_{IN} : $t_r, t_f < 5 \text{ ns}$
 ($Z_{out} = 50 \Omega$)
 Common Source
 $T_a = 25^\circ\text{C}$

(b) V_{IN}



(c) V_{OUT}

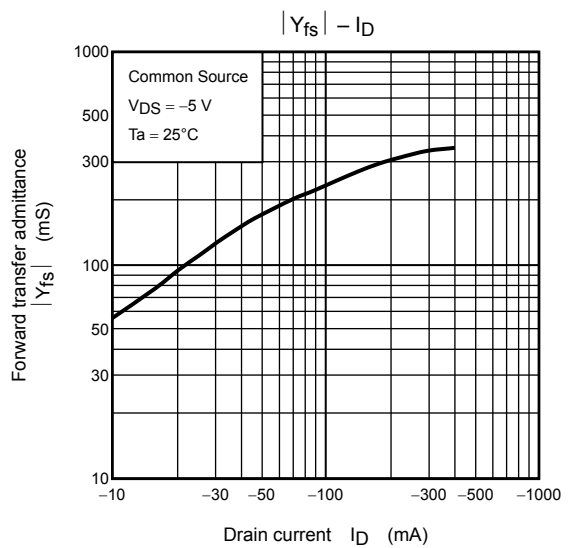
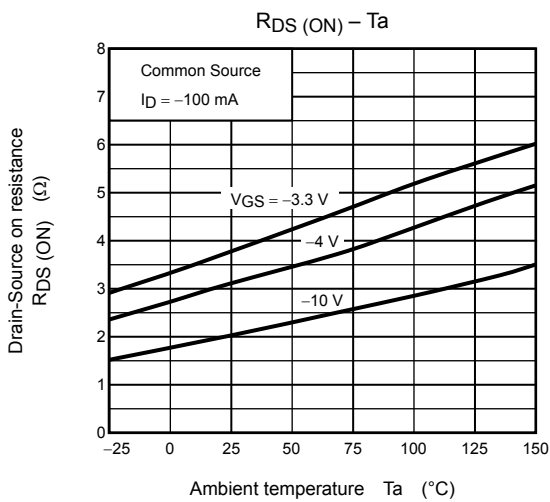
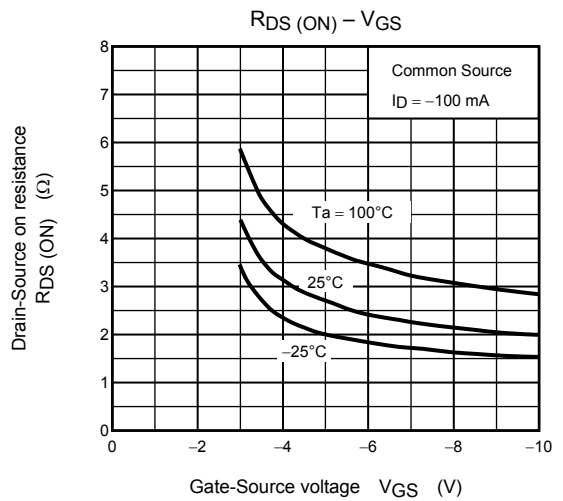
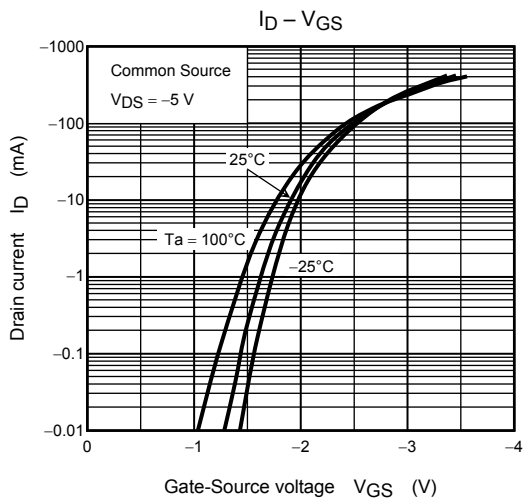
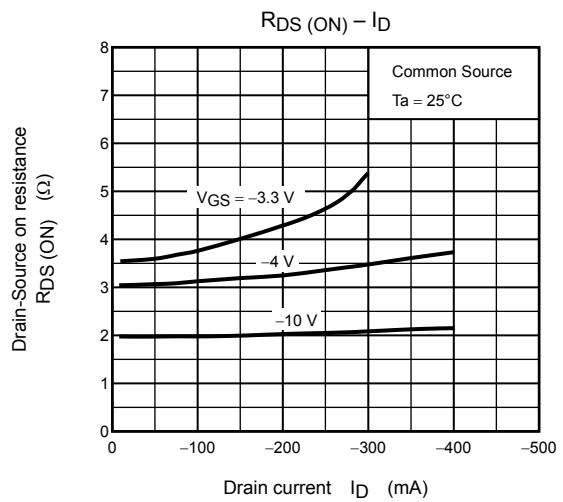
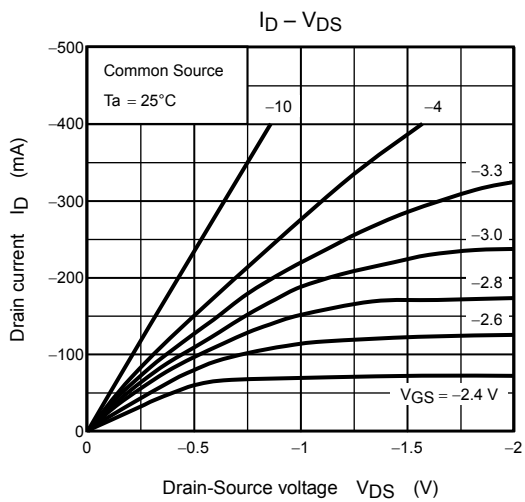


Precaution

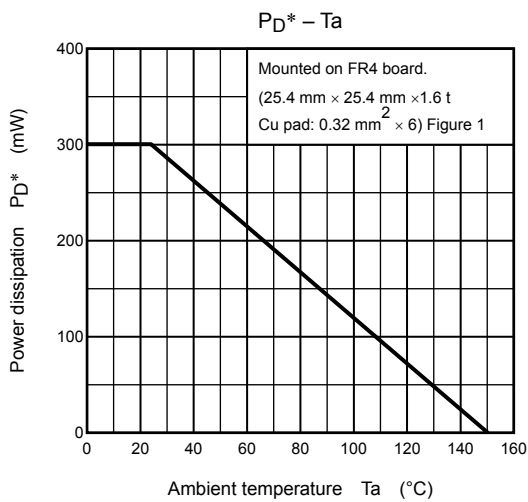
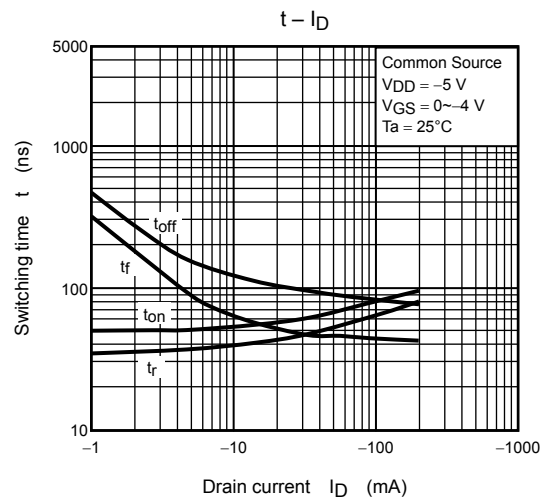
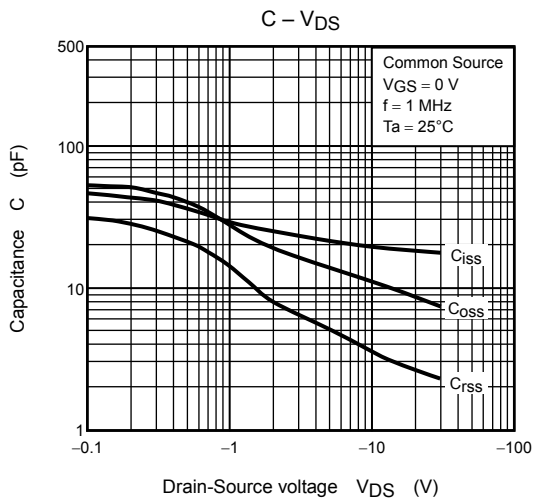
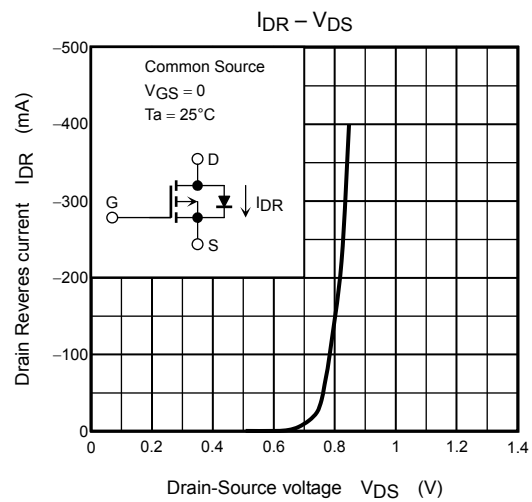
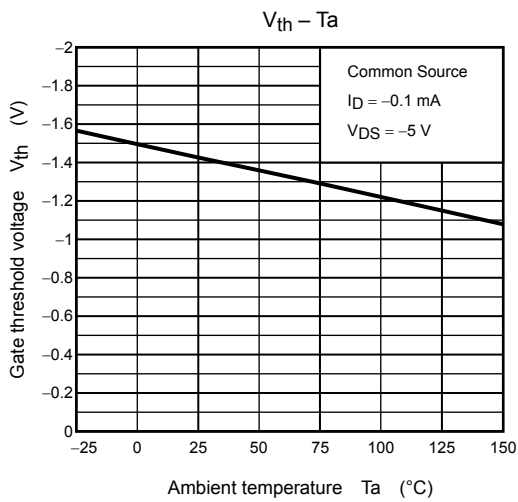
V_{th} can be expressed as voltage between gate and source when low operating current value is $I_D = -100 \mu\text{A}$ for this product. For normal switching operation, $V_{GS(on)}$ requires higher voltage than V_{th} and $V_{GS(off)}$ requires lower voltage than V_{th} . (Relationship can be established as follows: $V_{GS(off)} < V_{th} < V_{GS(on)}$)

Please take this into consideration for using the device.

(Q1, Q2 common)



(Q1, Q2 common)



*: Total rating

RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

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